

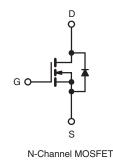
## K2381-VB Datasheet N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	200					
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	0.265				
Q <sub>g</sub> (Max.) (nC)	16					
Q <sub>gs</sub> (nC)	5					
Q <sub>gd</sub> (nC)	8					
Configuration	Single					

#### **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available





<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	200	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	10		
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		6.5	A	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	32		
Linear Derating Factor				0.24	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	36	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.2	A	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	3.7	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	37	W	
Peak Diode Recovery dV/dtc			dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>		
Mounting Torque	6 22 or 1	6.00 or M0 corow		10	lbf ⋅ in	
	6-32 or M3 screw		-	1.1	N ⋅ m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 1.0 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 7.2 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 9.2 \text{ A}$ , dl/dt  $\le 110 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.





THERMAL RESISTANCE RAT	TINGS								
PARAMETER	SYMBOL	TYP.		MAX.		UNIT			
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65			2011				
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 4.1				°C/W			
<b>SPECIFICATIONS</b> $T_J = 25 \ ^{\circ}C$ ,	unless otherw	vise noted			-		-		
PARAMETER	SYMBOL	TES	T CONDITI	ONS	MIN.	TYP.	MAX.	UNIT	
Static									
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	0 V, I <sub>D</sub> = 2	50 μΑ	200	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.13	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$			2.0	-	4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$			-	-	± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} =$	$V_{DS} = 200 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	25		
		$V_{DS}$ =160 V, $V_{GS}$ = 0 V, $T_{J}$ = 150 °C			-	-	250	μΑ	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub>	= 4.3 A <sup>b</sup>	-	0.265	-	Ω	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	50 V, I <sub>D</sub> =	4.3 A <sup>b</sup>	2.3	-	-	S	
Dynamic									
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ ,			-	560	-	-	
Output Capacitance	C <sub>oss</sub>	,	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$		-	260	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	110	-	pF		
Drain to Sink Capacitance	С	f = 1.0 MHz			-	12		-	
Total Gate Charge	Qg				-	-	16		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 9.2 \text{ /}$		-	-	4.4	nC	
Gate-Drain Charge	Q <sub>gd</sub>	See no		g. 6 and 13 <sup>b</sup>	-	-	7.7		
Turn-On Delay Time	t <sub>d(on)</sub>				-	8.8	-		
Rise Time	t <sub>r</sub>	$\begin{array}{l} {\sf V}_{\rm DD} \ = \ 100 \ {\sf V}, \ {\sf I}_{\rm D} = \ 9.2 \ {\sf A}, \\ {\sf R}_{\rm G} \ = \ 18 \ \Omega, \ {\sf R}_{\rm D} = \ 5.2 \ \Omega, \\ {\sf see \ fig. \ 10^b} \end{array}$		-	30	-	ns		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	19	-			
Fall Time	t <sub>f</sub>			-	20	-			
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH		
Internal Source Inductance	L <sub>S</sub>			-	7.5	-			
Drain-Source Body Diode Characteristic	cs								
Continuous Source-Drain Diode Current	١ <sub>S</sub>	MOSFET symbol showing the		-	10	-	A		
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode			-	32		-	
Body Diode Voltage	$V_{SD}$	$T_J = 25 \ ^{\circ}C,$	I <sub>S</sub> = 7.2 A,	$V_{GS} = 0 V^{b}$	-	-	2.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 9.2 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	130	260	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.65	1.3	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )						_D)	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

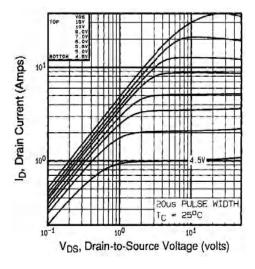


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

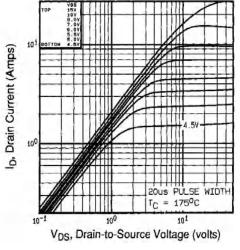


Fig. 2 - Typical Output Characteristics,  $T_C$  = 175  $^\circ C$ 

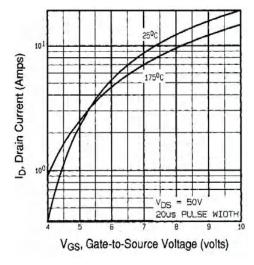


Fig. 3 - Typical Transfer Characteristics

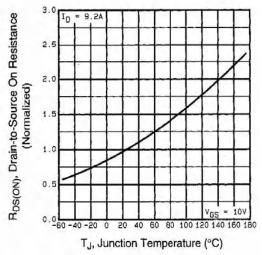


Fig. 4 - Normalized On-Resistance vs. Temperature



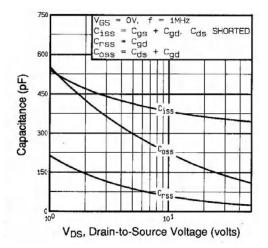


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

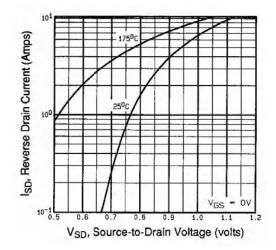


Fig. 7 - Typical Source-Drain Diode Forward Voltage

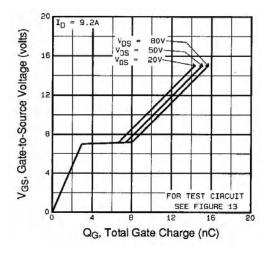


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

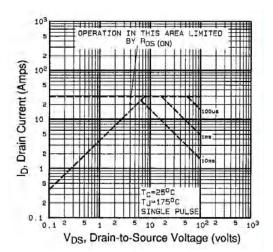


Fig. 5 - Fig. 8 - Maximum Safe Operating Area



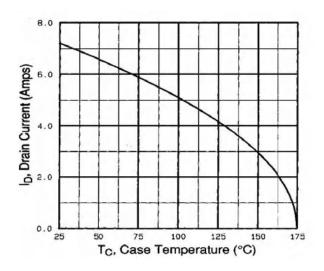


Fig. 9 - Maximum Drain Current vs. Case Temperature

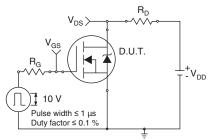


Fig. 10a - Switching Time Test Circuit

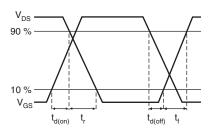
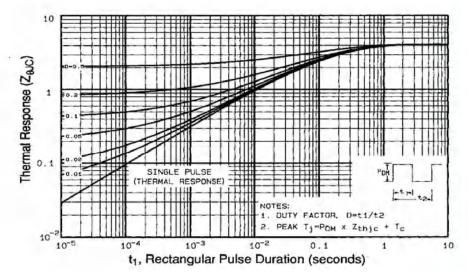
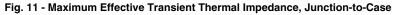
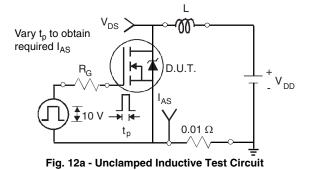


Fig. 10b - Switching Time Waveforms







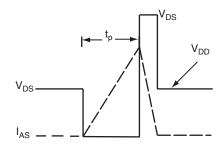
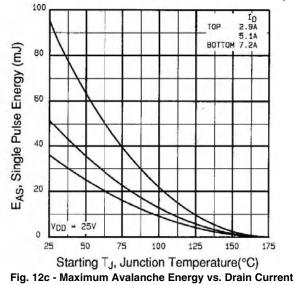
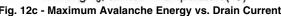


Fig. 12b - Unclamped Inductive Waveforms







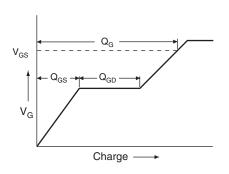
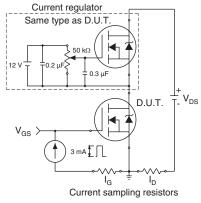
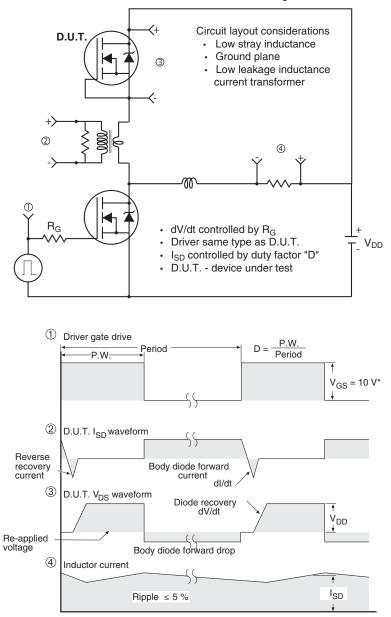


Fig. 13a - Basic Gate Charge Waveform









### Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel



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